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Metal to insulator quantum-phase transition in few-layered **ReS<sub>2</sub>.**<sup>1</sup> NIHAR PRADHAN, NHMFL, Tallahassee, FL-32310, USA, AMBER MCCREARY, Dept. of Physics, Penn State University, PA 16802, USA, DANIEL RHODES, ZHENGUANG LU, DMITRY SMIRNOV, EFSTRATIOS MANOUSAKIS, NHMFL, Tallahassee, FL-32310, USA, SIMIN FENG, Dept. of Physics, Penn State University, PA 16802, USA, RAJU NAMBURU, MADAN DUBEY, U.S. Army Research Laboratory, Adelphi, MD 20783, USA, ANGELA HIGHT WALKER, NIST, Gaithersburg, MD 20899, USA, HUMBERTO TER-RONES, Dept. of Physics, RPI, NY 12180, USA, MAURICIO TERRONES, Dept. of Physics, Penn State University, PA 16802, USA, VLADIMIR DOBROSAVL-JEVIC, LUIS BALICAS, NHMFL, Tallahassee, FL-32310, USA —  $ReS_2$  a layerindependent direct band-gap semiconductor of 1.5 eV implies a potential for its use in optoelectronic applications. Here, we present an overall evaluation of transport and anisotropic Raman of few-layered  $\operatorname{ReS}_2$  FET.  $\operatorname{ReS}_2$  exfoliated on SiO<sub>2</sub> behaves as an *n*-type semiconductor with an intrinsic carrier mobility surpassing  $\mu_i ~30 \text{ cm}^2/\text{Vs}$ at T = 300 K which increases up to ~350 cm<sup>2</sup>/vs at 2 K. Semiconducting behavior is observed at low electron densities n, but at high values of n the resistivity decreases by a factor >7 upon cooling to 2 K and displays a metallic  $T^2$ -dependence. The electric-field induced metallic state observed in  $MoS_2$  was recently claimed to result from a percolation type of transition. Instead, through a scaling analysis of the conductivity as a function of T and n, we find that the metallic state of ReS<sub>2</sub> results from a second-order metal to insulator transition driven by electronic correlations.

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